

Amendments To The Claims

LISTING OF CLAIMS

Claims 1-20 (canceled)

21. (previously presented) A system for testing an electronic module having a plurality of terminal contacts comprising:

- a test circuitry configured to generate and apply test signals to the module;

- a board;

- a plurality of test contactors on the board configured to electrically engage the terminal contacts and movable from a first position to a second position, each test contactor comprising a coiled spring having a terminal portion configured to electrically engage a terminal contact with a spring force generated by the coiled spring; and

- a flex circuit in electrical communication with the test contactors and the test circuitry.

22. (previously presented) The system of claim 21 wherein the test contactors comprise a base slidably mounted to the board.

23. (previously presented) The system of claim 21 wherein the test contactors comprise a molded plastic base slidably mounted to the board and the coiled springs are embedded in the molded plastic.

24. (previously presented) The system of claim 21 wherein the terminal portion is configured to penetrate the terminal contact.

Claims 25-46 (canceled)

47. (previously presented) A pass through test contactor for testing an electronic module having a plurality of terminal contacts comprising:

a base movable from a first position to a second position;

a plurality of spring contacts on the base configured to electrically engage the terminal contacts and movable from the first position to the second position, each test contactor comprising a coiled spring and a terminal portion configured to electrically engage a terminal contact with a spring force generated by the coiled spring and with a zero insertion force on the module; and

a flex circuit in electrical communication with the spring contacts.

48. (Original) The test contactor of claim 47 wherein the base comprises molded plastic and the coiled springs are embedded in the molded plastic.

49. (Original) The test contactor of claim 47 wherein the module comprises an element selected from the group consisting of semiconductor memory modules, multi chip modules, semiconductor carriers, semiconductor packages, and microprocessors.

50. (Original) The test contactor of claim 47 further comprising an interface board comprising support members for movable mounting the base.

51. (previously presented) The test contactor of claim 47 wherein the terminal portion is configured to penetrate the terminal contact.

52. (previously presented) A test system for testing an electronic module having a plurality of terminal contacts comprising:

a test circuitry configured to apply test signals to the module;

a board; and

a plurality of coiled spring contacts on the board movable from a first position in which the terminal contacts can be aligned with the coiled spring contacts with a zero insertion force on the module, to a second position in which the coiled spring contacts electrically engage the terminal contacts, each coiled spring contact comprising an end portion in electrical communication with the test circuitry and a tip portion configured in the first position to be spaced from a terminal contact and in the second position to electrically engage the terminal contact.

53. (previously presented) The system of claim 52 further comprising a flex circuit electrically connecting the coiled spring contacts to the test circuitry.

54. (previously presented) The system of claim 52 further comprising a test handler configured to move the coiled spring contacts from the first position to the second position.

55. (previously presented) The system of claim 52 wherein the tip portion is configured to penetrate the terminal contact.

56. (previously presented) The system of claim 52 further comprising a movable base on the board configured to support and move the coiled spring contacts from the first position to the second position.

57. (previously presented) A system for testing an electronic module having a plurality of terminal contacts comprising:

a test circuitry;

a test handler;

a board on the test handler;

a base on the board movable by the test handler from a first position to a second position; and

a plurality of test contactors on the base in electrical communication with the test circuitry configured to electrically engage the terminal contacts, each test contactor comprising a coiled spring having a terminal portion configured to align with a terminal contact in the first position and to electrically engage the terminal contact in the second position with a spring force exerted by the coiled spring.

58. (previously presented) The system of claim 57 further comprising a flex circuit in electrical communication with the test contactors and the test circuitry.

59. (previously presented) The system of claim 57 wherein the terminal portion is configured to penetrate the terminal contact with the spring force.

60. (previously presented) The system of claim 57 further comprising a drive mechanism on the test handler configured to move the base from the first position to the second position.